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(54) **CLOCK CONTROLLER FOR AT-SPEED TESTING OF SCAN CIRCUITS**

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(57) **ABSTRACT**

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(52) **U.S. Cl.** ..... 714/731; 714/729

(58) **Field of Classification Search** ..... 375/376;  
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See application file for complete search history.

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**29 Claims, 7 Drawing Sheets**

